## IAP20 Rec'd FGT.770 19 JAN 2006

Docket No.: 034337-0429 <u>PATENT</u>

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Ion BENEA, et al. : Confirmation No.: Not yet assigned

Application No.: Not yet assigned : Group Art Unit: Not yet assigned

Filed: January 19, 2006 : Examiner: Not yet assigned

For: APPARATUS FOR MEASURING THE CRUSHING STRENGTH OF MICRON

**SUPERABRASIVES** 

## PRELIMINARY AMENDMENT

Mail Stop Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Prior to examination of the above-referenced application, please amend the application as follows:

Amendments to the Specification begin on page 2 of this paper.

**Remarks** begin on page 3 of this paper.